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**Complete if Known**

Application Number	10/777,094
Filing Date	February 13, 2004
First Named Inventor	Gordon ROBERTS
Art Unit	3631
Examiner Name	N/A
Attorney Docket Number	85827-90

## U. S. PATENT DOCUMENTS

**FOREIGN PATENT DOCUMENTS**

**Examiner  
Signature**

/Helene Tayong/

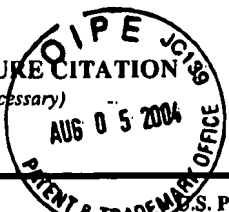
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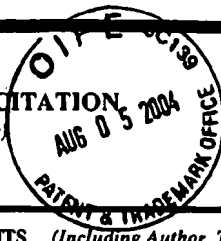
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<b>INFORMATION DISCLOSURE CITATION</b> <i>(Use several sheets if necessary)</i>				Docket Number (Optional) <b>85827-90</b>		Application Number <b>10/777,094</b>		
				Applicant(s) <b>Gordon ROBERT et al.</b>				
				Filing Date <b>February 13, 2004</b>		Group Art Unit <b>3631</b>		
U.S. PATENT DOCUMENTS								
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
/H.T./	1.	US 5,646,521	07-08-1997	Rosenthal et al.				
U.S. PATENT APPLICATION PUBLICATIONS								
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
/H.T./	2.	US 2003/0128141 A1	07-10-2003	Asami				
FOREIGN PATENT DOCUMENTS								
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
/H.T./	3.	JP 07005213	10-01-1995	Japan (abstract)				
/H.T./	4.	JP 2002217732	02-08-2002	Japan (abstract)				
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>								
/H.T./	5.	Erratum to "Improving the dynamic measurements of ADCs using the 2-ADC method" Computer standard and interfaces, 23 (2001) 239-243, vol. 22 issue 4, 281 - 286, Philippe Cauvet.						
/H.T./	6.	"Improving the dynamic measurements of ADCs using the 2-ADC method", Computer standards & interfaces, 22 (2000) 281-286, Philippe Cauvet.						
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INITIAL

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

/H.T./

7.

XP-000471158; "Real-Time Digital Signal Processing in a Mixed-Signal LSI Test System"; 1266 Hewlett-Packard Journal, 45 (1994) October, No. 5, Palo Alto, CA, U.S. (pages 59-63).

/H.T./

8.

XP-001125859; "Channel Linearity Mismatch Effects in Time-Interleaved ADC Systems" IEICE TRANS. FUNDAMENTALS, Vol. E85-A, No. 4 April, 2002, (pages 749-756).

/H.T./

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International Search Report of PCT/CA2004/000188 dated June 30, 2004.

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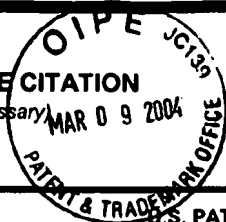
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ATTY DOCKET NO.  
85827-90

SERIAL NO.  
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Applicant: Gordon ROBERTS et al.

FILING  
February 13, 2004

GROUP  
N/A

## **U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/H.T./	US 6,356,850 B1	03-12-2002	Wilstrup et al.			

## **FOREIGN PATENT DOCUMENTS**

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

## **OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

/H.T./	2.	Robert H. Walden, Analog-to-Digital Converter Survey and Analysis, IEEE Journal on Selected Areas in Communications, Vol. 17, No. 4, April 1999.
/H.T./	3.	M.M. Hafed, N. Abaskharoun, and G.W. Roberts, A stand-alone integrated test core for time and frequency domain measurements, International Test Conference, pp. 1190-1199, 2001.

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*EXAMINER INITIAL	OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>		
/H.T./	4.	M. Burns and G.W. Roberts, An Introduction to Mixed-Signal IC Test and Measurement, Oxford Press, pp.166-170, 2001.	
/H.T./	5.	N. Kurosawa et al., Explicit Analysis of Channel Mismatch Effects in Time-Interleaved ADC Systems, IEEE Transaction on Circuits and Systems-I: Fundamental Theory and Applications, Vol. 48, No. 3, pp. 261-271, March 2001.	
/H.T./	6.	Yves Langard, Jean-Luc Balat and Jacques Durant, An Improved Method of ADC Jitter Measurement, International Test Conference, 1994.	
/H.T./	7.	Philippe Cauvet and Loïc Hamonou, An Improving the Dynamic Measurements of ADC's using the 2-ADC Method, Teradyne Users Group, 2001.	
	8.	Search Results	
EXAMINER		DATE CONSIDERED	
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